## **AMENDMENTS TO THE CLAIMS**

1. (Currently Amended) A sample observation method comprising a step of recognizing the <u>an</u> image of an object in the <u>a</u> transmission electron beam image of a sample by comparing it with a previously stored reference image;

said sample observation method characterized by further comprising the steps of:
specifying an the object in said transmission electron beam image wherein multiple
pairs of transmission electron beam images of multiple transmission electron beam images
of multiple objects having a different angle with respect to the optical axis are stored in said
reference images for said objects;

computing the a correlation between said specified object image and a the stored reference image; and

displaying the result of computation for different tilt angles[.];

wherein multiple pairs of transmission electron beam images of multiple transmission electron beam images of multiple objects each having a different tilt angle with respect to the optical axis are stored as said reference images for said object.

2. (Currently Amended) A sample observation method comprising a step of recognizing the <u>an</u> image of an object in the <u>a</u> transmission electron beam image of a sample by comparing it with a previously stored reference image;

said sample observation method characterized by further comprising the steps of:
specifying an the object in said transmission electron beam image wherein multiple
images formed by polar coordinate conversion of transmission electron beam images of
multiple objects are stored as said reference images;

carrying out polar coordinate conversion of the image of said specified object; computing the a correlation of the images between said specified object image and the stored reference image having been subjected to the polar coordinate conversion and said reference image; and

displaying the result of computation for different tilt angles[.];

wherein multiple pairs of transmission electron beam images of multiple transmission electron beam images of multiple objects having a different tilt angle with respect to the optical axis are stored as said reference images for said objects.

- 3. (Original) The sample observation method according to Claim 2 further characterized in that the transmission electron beam image of said object consists of multiple pairs of transmission electron beam images of the objects having a different tilt angle with respect to the optical axis.
- 4. (Currently Amended) The sample observation method according to Claim 2 further comprising a step of specifying the fulcrum a fulcrum for rotation in the polar coordinate conversion of said object image, in said transmission electron beam image.
- 5. (Original) The sample observation method according to any one of Claims 1 through 3 further characterized in that said result of computation is displayed in terms of agreement between said object image and said reference image.
- 6. (Currently Amended) A sample observation method for searching the same objects in multiple objects in the transmission electron beam images of a sample, said method characterized by comprising steps of:

selecting multiple objects in said transmission electron beam images of a sample; carrying out polar coordinate conversion of each of said selected multiple object images;

specifying one of said multiple objects;

computing the a correlation between the image of the specified object subsequent subjected to polar coordinate conversion and the images of other objects subsequent subjected to the polar coordinate conversion; and

displaying the result of computation[.];

wherein multiple pairs of transmission electron beam images of multiple transmission electron beam images of said other objects each having a different tilt angle with respect to the optical axis are stored.

- 7. (Original) The sample observation method according to any one of Claims 1 through 3 further characterized in that the apparatus data at the time of photographing the transmission electron beam image of a sample is stored in a one-to-one relationship with the transmission electron beam image of said sample.
- 8. (Original) The sample observation method according to Claim 7 further characterized in that said transmission electron beam image of the sample is stored as an image of TIFF format containing a tag area, and said apparatus data is stored in said tag area.
- 9. (Original) The sample observation method according to Claim 7 further characterized in that the apparatus data stored in said tag area is set on the transmission electron microscope, and the conditions for photographing the transmission electron beam image containing said object are reproduced.
  - 10. (Currently Amended) A transmission electron microscope comprising: an electron gun;
- an irradiation lens for applying to a sample the electron beam discharged from said electron gun; and
- a controller for storing the electron beam image having passed through said sample; said transmission electron microscope further characterized in that said controller stores a set of multiple transmission electron microscope images having different irradiation angles of said electron beam as <u>a</u> reference <u>image</u> in advance; and
- electron beam is applied to said sample to form a set of multiple transmission electron microscope images having different irradiation angles; thereby computing

correlation between the set of said multiple transmission electron microscope images and said reference image.

10. (Canceled)